## Notice of References Cited Application/Control No. 10/757,584 Examiner William Boddie Applicant(s)/Patent Under Reexamination ONO ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,237,311	08-1993	Mailey et al.	345/167
*	В	US-2002/0054011	05-2002	Bruneau et al.	345/156
*	С	US-6,909,422	06-2005	Yokoji et al.	345/167
*	D	US-6,144,370	11-2000	Eleyan et al.	345/167
*	Е	US-6,825,831	11-2004	Passaro, Richard M.	345/167
*	F	US-5,914,705	06-1999	Johnson et al.	345/163
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R	·				
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	C							
	>							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.